Microsemi Corporation - A1425A-1PLG84C Datasheet

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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications,

Details	
Product Status	Obsolete
Number of LABs/CLBs	310
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	70
Number of Gates	2500
Voltage - Supply	4.5V ~ 5.5V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 70°C (TA)
Package / Case	84-LCC (J-Lead)
Supplier Device Package	84-PLCC (29.31x29.31)
Purchase URL	https://www.e-xfl.com/product-detail/microsemi/a1425a-1plg84c

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Device/Package	Speed Grade[1]				Application[1]			
	Std.	–1	–2	–3	C	I	M	B
A14V40A Device								
84-Pin Plastic Leaded Chip Carrier (PLCC)	✓	–	–	–	✓	–	–	–
100-Pin Very Thin Quad Flatpack (VQFP)	✓	–	–	–	✓	–	–	–
160-Pin Plastic Quad Flatpack (PQFP)	✓	–	–	–	✓	–	–	–
176-Pin Thin Quad Flatpack (TQFP)	✓	–	–	–	✓	–	–	–
A1460A Device								
160-Pin Plastic Quad Flatpack (PQFP)	✓	✓	D	D	✓	✓	–	–
176-Pin Thin Quad Flatpack (TQFP)	✓	✓	D	D	✓	✓	–	–
196-Pin Ceramic Quad Flatpack (CQFP)	✓	✓	–	–	✓	–	✓	✓
207-Pin Ceramic Pin Grid Array (CPGA)	✓	✓	D	D	✓	–	✓	✓
208-Pin Plastic Quad Flatpack (PQFP)	✓	✓	D	D	✓	✓	–	–
225-Pin Plastic Ball Grid Array (BGA)	D	D	D	D	D	–	–	–
A14V60A Device								
160-Pin Plastic Quad Flatpack (PQFP)	✓	–	–	–	✓	–	–	–
176-Pin Thin Quad Flatpack (TQFP)	✓	–	–	–	✓	–	–	–
208-Pin Plastic Quad Flatpack (PQFP)	✓	–	–	–	✓	–	–	–
A14100A Device								
208-Pin Power Quad Flatpack (RQFP)	✓	✓	D	D	✓	✓	–	–
257-Pin Ceramic Pin Grid Array (CPGA)	✓	✓	D	D	✓	–	✓	✓
313-Pin Plastic Ball Grid Array (BGA)	✓	✓	D	D	✓	–	–	–
256-Pin Ceramic Quad Flatpack (CQFP)	✓	✓	–	–	✓	–	✓	✓
A14V100A Device								
208-Pin Power Quad Flatpack (RQFP)	✓	–	–	–	✓	–	–	–
313-Pin Plastic Ball Grid Array (BGA)	✓	–	–	–	✓	–	–	–

Notes:

1. *Applications:*
   C = Commercial
   I = Industrial
   M = Military
2. *Commercial only*

Availability:
✓ = Available
P = Planned
– = Not planned
D = Discontinued

Speed Grade:
–1 = Approx. 15% faster than Std.
–2 = Approx. 25% faster than Std.
–3 = Approx. 35% faster than Std.
(–2 and –3 speed grades have been discontinued.)

The S-module contains a full implementation of the C-module plus a clearable sequential element that can either implement a latch or flip-flop function. The S-module can therefore implement any function implemented by the C-module. This allows complex combinatorial-sequential functions to be implemented with no delay penalty. The Designer Series Development System will automatically combine any C-module macro driving an S-module macro into the S-module, thereby freeing up a logic module and eliminating a module delay.

The clear input CLR is accessible from the routing channel. In addition, the clock input may be connected to one of three clock networks: CLKA, CLKB, or HCLK. The C-module and S-module functional descriptions are shown in Figure 2-2 and Figure 2-3 on page 2-2. The clock selection is determined by a multiplexer select at the clock input to the S-module.

I/Os

I/O Modules

I/O modules provide an interface between the array and the I/O Pad Drivers. I/O modules are located in the array and access the routing channels in a similar fashion to logic modules. The I/O module schematic is shown in Figure 4. The signals DataIn and DataOut connect to the I/O pad driver.

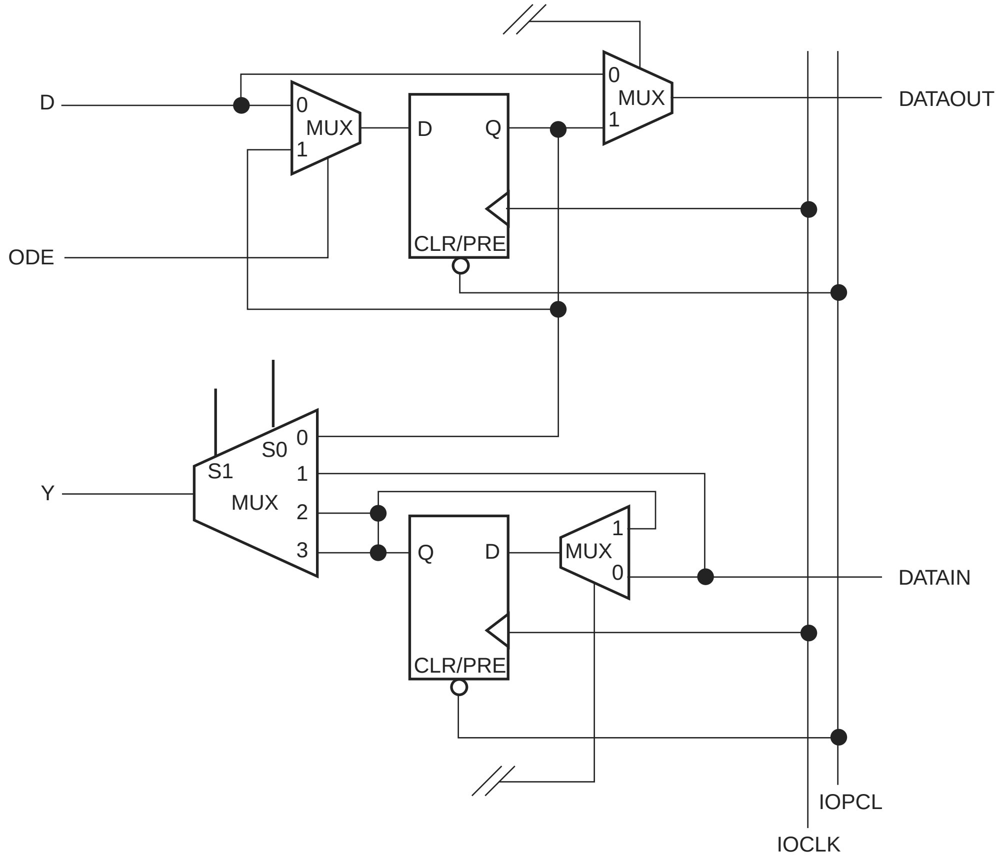


Figure 2-4 • **Functional Diagram for I/O Module**

Each I/O module contains two D-type flip-flops. Each flip-flop is connected to the dedicated I/O clock (IOCLK). Each flip-flop can be bypassed by nonsequential I/Os. In addition, each flip-flop contains a data enable input that can be accessed from the routing channels (ODE and IDE). The asynchronous preset/clear input is driven by the dedicated preset/clear network (IOPCL). Either preset or clear can be selected individually on an I/O module by I/O module basis.

Antifuse Connections

An antifuse is a “normally open” structure as opposed to the normally closed fuse structure used in PROMs or PALs. The use of antifuses to implement a programmable logic device results in highly testable structures as well as an efficient programming architecture. The structure is highly testable because there are no preexisting connections; temporary connections can be made using pass transistors. These temporary connections can isolate individual antifuses to be programmed as well as isolate individual circuit structures to be tested. This can be done both before and after programming. For example, all metal tracks can be tested for continuity and shorts between adjacent tracks, and the functionality of all logic modules can be verified.

Four types of antifuse connections are used in the routing structure of the ACT 3 array. (The physical structure of the antifuse is identical in each case; only the usage differs.)

Table 2-1 shows four types of antifuses.

***Table 2-1* • Antifuse Types**

Type	Description
XF	Horizontal-to-vertical connection
HF	Horizontal-to-horizontal connection
VF	Vertical-to-vertical connection
FF	"Fast" vertical connection

Examples of all four types of connections are shown in Figure 2-7 on page 2-6 and Figure 2-8 on page 2-6.

Module Interface

Connections to Logic and I/O modules are made through vertical segments that connect to the module inputs and outputs. These vertical segments lie on vertical tracks that span the entire height of the array.

Module Input Connections

The tracks dedicated to module inputs are segmented by pass transistors in each module row. During normal user operation, the pass transistors are inactive, which isolates the inputs of a module from the inputs of the module directly above or below it. During certain test modes, the pass transistors are active to verify the continuity of the metal tracks. Vertical input segments span only the channel above or the channel below. The logic modules are arranged such that half of the inputs are connected to the channel above and half of the inputs to segments in the channel below, as shown in Figure 2-9.

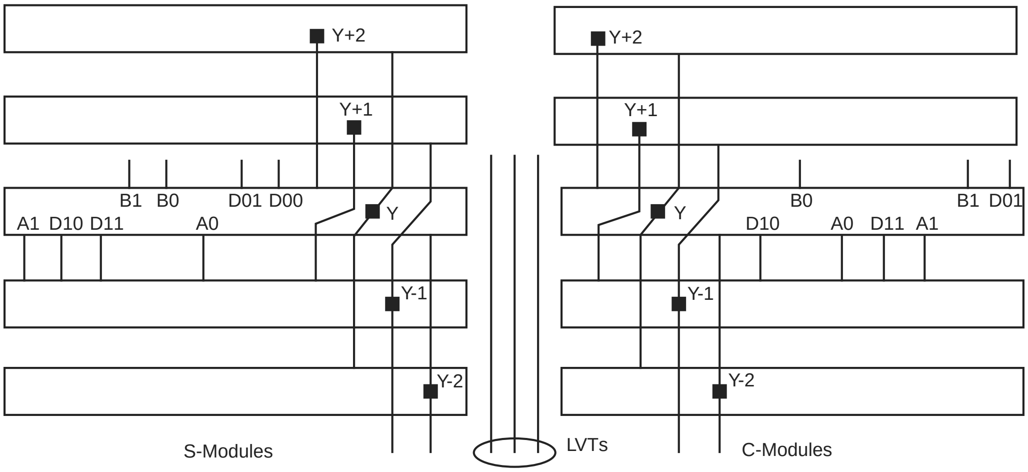


***Figure 2-9* • Logic Module Routing Interface**

Module Output Connections

Module outputs have dedicated output segments. Output segments extend vertically two channels above and two channels below, except at the top or bottom of the array. Output segments twist, as shown in Figure 10, so that only four vertical tracks are required.

LVT Connections

Outputs may also connect to nondedicated segments called Long Vertical Tracks (LVTs). Each module pair in the array shares four LVTs that span the length of the column. Any module in the column pair can connect to one of the LVTs in the column using an FF connection. The FF connection uses antifuses connected directly to the driver stage of the module output, bypassing the isolation transistor. FF antifuses are programmed at a higher current level than HF, VF, or XF antifuses to produce a lower resistance value.

Antifuse Connections

In general every intersection of a vertical segment and a horizontal segment contains an unprogrammed antifuse (XF-type). One exception is in the case of the clock networks.

Clock Connections

To minimize loading on the clock networks, a subset of inputs has antifuses on the clock tracks. Only a few of the C-module and S-module inputs can be connected to the clock networks. To further reduce loading on the clock network, only a subset of the horizontal routing tracks can connect to the clock inputs of the S-module.

Programming and Test Circuits

The array of logic and I/O modules is surrounded by test and programming circuits controlled by the temporary special I/O pins MODE, SDI, and DCLK. The function of these pins is similar to all ACT family devices. The ACT 3 family also includes support for two Actionprobe® circuits, allowing complete observability of any logic or I/O module in the array using the temporary special I/O pins, PRA and PRB.

5 V Operating Conditions

Table 2-2 **• Absolute Maximum Ratings[1], Free Air Temperature Range**

Symbol	Parameter	Limits	Units
VCC	DC supply voltage	–0.5 to +7.0	V
VI	Input voltage	–0.5 to VCC + 0.5	V
VO	Output voltage	–0.5 to VCC + 0.5	V
IIO	I/O source sink current[2]	±20	mA
T_{STG}	Storage temperature	–65 to +150	°C

Notes:

1. *Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. Exposure to absolute maximum rated conditions for extended periods may affect device reliability. Device should not be operated outside the recommended operating conditions.*
2. *Device inputs are normally high impedance and draw extremely low current. However, when input voltage is greater than VCC + 0.5 V for less than GND –0.5 V, the internal protection diodes will forward bias and can draw excessive current.*

Table 2-3 **• Recommended Operating Conditions**

Parameter	Commercial	Industrial	Military	Units
Temperature range*	0 to +70	–40 to +85	–55 to +125	°C
5 V power supply tolerance	±5	±10	±10	%VCC

*Note: *Ambient temperature (T_A) is used for commercial and industrial; case temperature (T_C) is used for military.*

Table 2-4 **• Electrical Specifications**

Symbol	Parameter	Test Condition	Commercial		Industrial		Military		Units
			Min.	Max.	Min.	Max.	Min.	Max.	
VOH[1,2]	High level output	IOH = –4 mA (CMOS)	–	–	3.7	–	3.7	–	V
		IOH = –6 mA (CMOS)	3.84						V
		IOH = –10 mA (TTL)[3]	2.40						V
VOL[1,2]	Low level output	IOL = +6 mA (CMOS)		0.33		0.4		0.4	V
		IOL = +12 mA (TTL)[3]		0.50					
VIH	High level input	TTL inputs	2.0	VCC + 0.3	2.0	VCC + 0.3	2.0	VCC + 0.3	V
VIL	Low level input	TTL inputs	–0.3	0.8	–0.3	0.8	–0.3	0.8	V
IIN	Input leakage	VI = VCC or GND	–10	+10	–10	+10	–10	+10	µA
IOZ	3-state output leakage	VO = VCC or GND	–10	+10	–10	+10	–10	+10	µA
C_{IO}	I/O capacitance[3,4]			10		10		10	pF
ICC(S)	Standby VCC supply current (typical = 0.7 mA)			2		10		20	mA
ICC(D)	Dynamic VCC supply current. See the Power Dissipation section.								

Notes:

1. *Microsemi devices can drive and receive either CMOS or TTL signal levels. No assignment of I/Os as TTL or CMOS is required.*
2. *Tested one output at a time, VCC = minimum.*
3. *Not tested; for information only.*
4. *VOUT = 0 V, f = 1 MHz*
5. *Typical standby current = 0.7 mA. All outputs unloaded. All inputs = VCC or GND.*

3.3 V Operating Conditions

***Table 2-5* • Absolute Maximum Ratings[1], Free Air Temperature Range**

Symbol	Parameter	Limits	Units
VCC	DC supply voltage	–0.5 to +7.0	V
VI	Input voltage	–0.5 to VCC + 0.5	V
VO	Output voltage	–0.5 to VCC + 0.5	V
IIO	I/O source sink current[2]	±20	mA
T_{STG}	Storage temperature	–65 to +150	°C

Notes:

1. *Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. Exposure to absolute maximum rated conditions for extended periods may affect device reliability. Device should not be operated outside the recommended operating conditions.*
2. *Device inputs are normally high impedance and draw extremely low current. However, when input voltage is greater than VCC + 0.5 V for less than GND –0.5 V, the internal protection diodes will forward bias and can draw excessive current.*

***Table 2-6* • Recommended Operating Conditions**

Parameter	Commercial	Units
Temperature range*	0 to +70	°C
Power supply tolerance	3.0 to 3.6	V

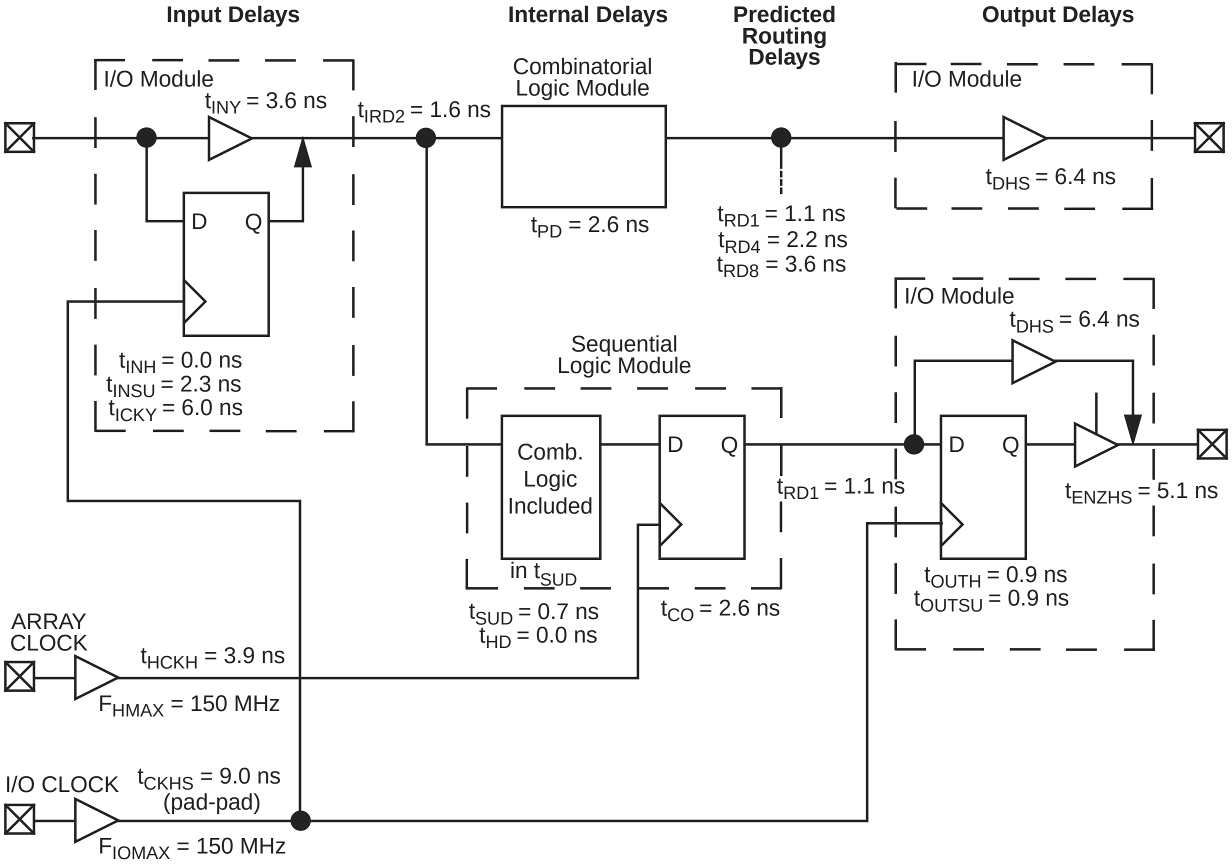
*Note: *Ambient temperature (T_A) is used for commercial.*

***Table 2-7* • Electrical Specifications**

Parameter		Commercial		Units
		Min.	Max.	
VOH[1]	IOH = –4 mA	2.15	–	V
	IOH = –3.2 mA	2.4		V
VOL[1]	IOL = 6 mA		0.4	V
VIL		–0.3	0.8	V
VIH		2.0	VCC + 0.3	V
Input transition time t_R, t_F[2]	VI = VCC or GND	–10	+10	µA
C_{IO} I/O Capacitance[2,3]			10	pF
Standby current, ICC[4] (typical = 0.3 mA)			0.75	mA
Leakage current[5]		–10	10	µA

1. *Only one output tested at a time. VCC = minimum.*
2. *Not tested; for information only.*
3. *Includes worst-case 84-pin PLCC package capacitance. VOUT = 0 V, f - 1 MHz.*
4. *Typical standby current = 0.3 mA. All outputs unloaded. All inputs = VCC or GND.*
5. *VO, VIN = VCC or GND*

ACT 3 Timing Model



Note: Values shown for A1425A –1 speed grade device.

Figure 2-10 • **Timing Model**

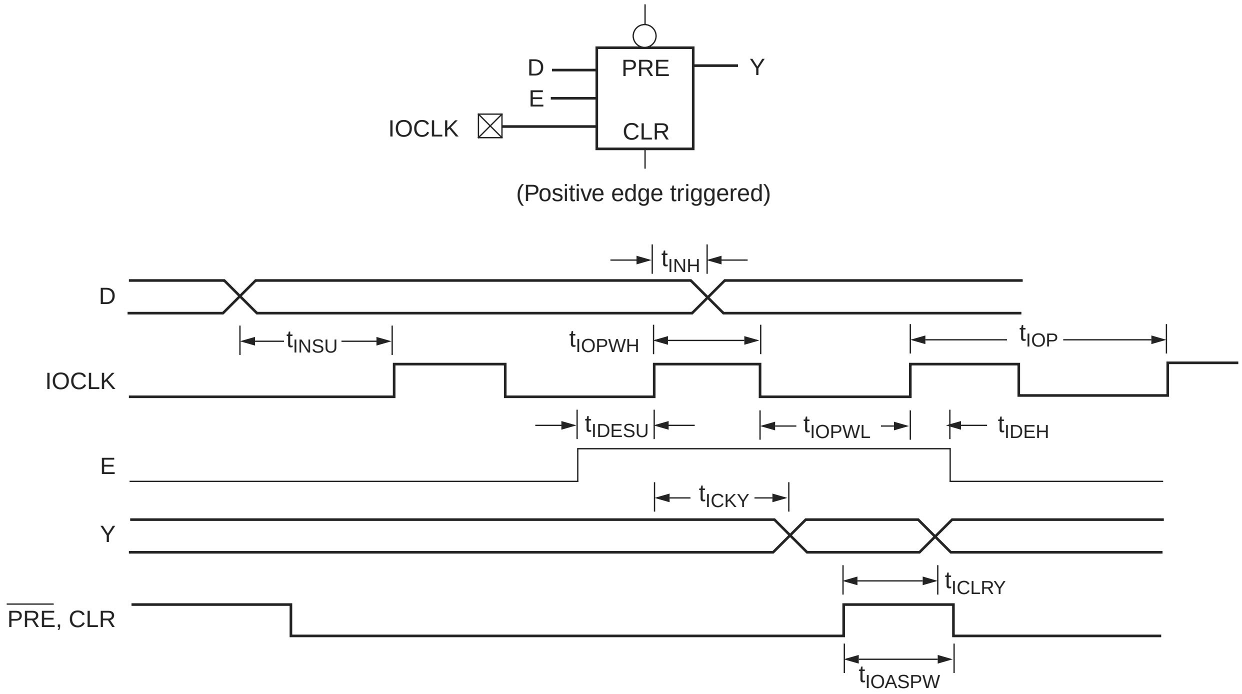


Figure 2-16 • **I/O Module: Sequential Input Timing Characteristics**

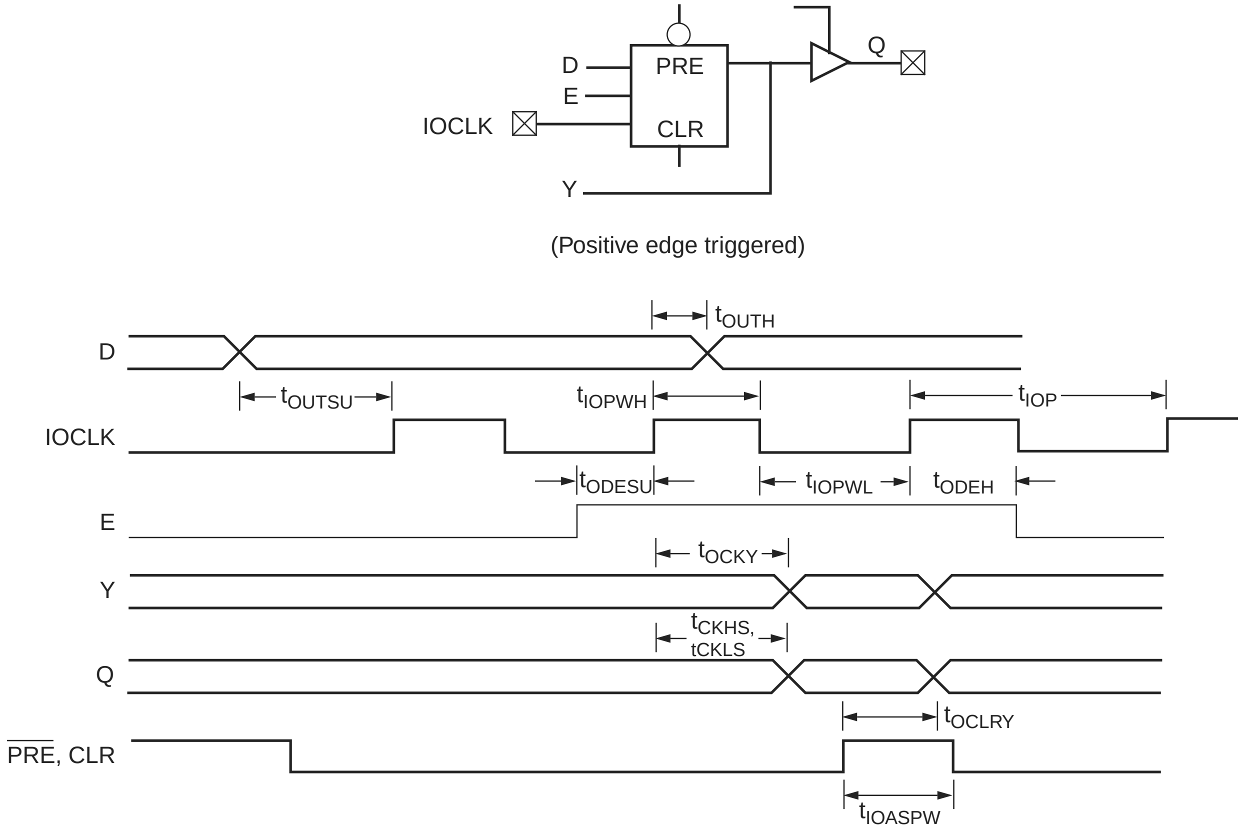


Figure 2-17 • **I/O Module: Sequential Output Timing Characteristics**

Timing Derating

ACT 3 devices are manufactured in a CMOS process. Therefore, device performance varies according to temperature, voltage, and process variations. Minimum timing parameters reflect maximum operating voltage, minimum operating temperature, and best-case processing. Maximum timing parameters reflect minimum operating voltage, maximum operating temperature, and worst-case processing.

***Table 2-15* • Timing Derating Factor (Temperature and Voltage)**

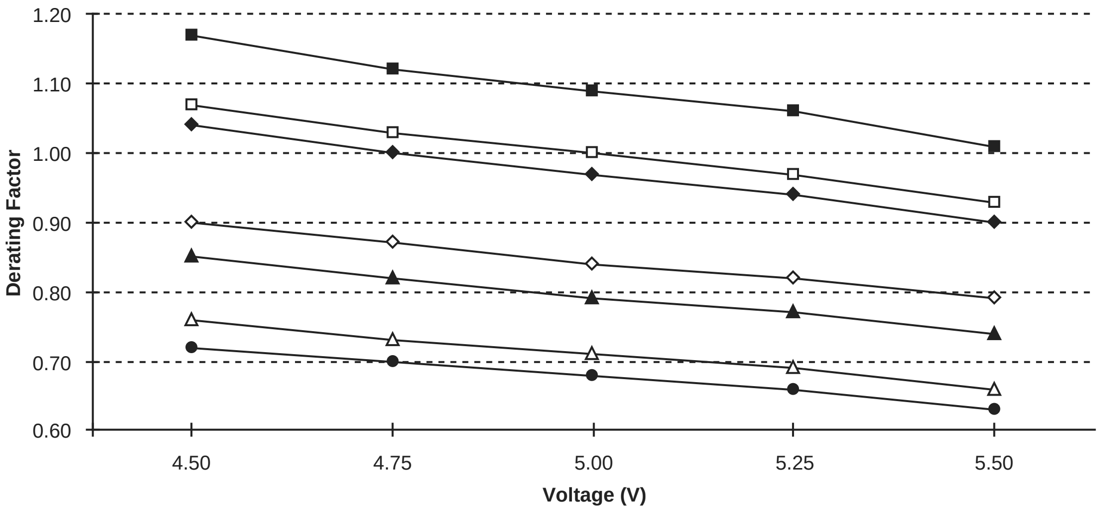
(Commercial Minimum/Maximum Specification) x	**Industrial**		**Military**	
	Min.	**Max.**	**Min.**	Max.
	0.66	1.07	0.63	1.17

***Table 2-16* • Timing Derating Factor for Designs at Typical Temperature (T_J = 25°C) and Voltage (5.0 V)**

(Commercial Maximum Specification) x	0.85

***Table 2-17* • Temperature and Voltage Derating Factors (normalized to Worst-Case Commercial, TJ = 4.75 V, 70°C)**

	–55	**–40**	**0**	**25**	**70**	**85**	**125**
4.50	0.72	0.76	0.85	0.90	1.04	1.07	1.117
4.75	0.70	0.73	0.82	0.87	1.00	1.03	1.12
5.00	0.68	0.71	0.79	0.84	0.97	1.00	1.09
5.25	0.66	0.69	0.77	0.82	0.94	0.97	1.06
5.50	0.63	0.66	0.74	0.79	0.90	0.93	1.01



Note: This derating factor applies to all routing and propagation delays.

***Figure 2-18* • Junction Temperature and Voltage Derating Curves (normalized to Worst-Case Commercial, TJ = 4.75 V, 70°C)**

A1425A, A14V25A Timing Characteristics (continued)

***Table 2-23* • A1425A, A14V25A Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C**

I/O Module Input Propagation Delays		**–3 Speed[1]**		**–2 Speed[1]**		**–1 Speed**		**Std. Speed**		**3.3 V Speed[1]**		**Units**
Parameter/Description		**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	
t_{INY}	Input Data Pad to Y		2.8		3.2		3.6		4.2		5.5	ns
t_{ICKY}	Input Reg IOCLK Pad to Y		4.7		5.3		6.0		7.0		9.2	ns
t_{OCKY}	Output Reg IOCLK Pad to Y		4.7		5.3		6.0		7.0		9.2	ns
t_{ICLRY}	Input Asynchronous Clear to Y		4.7		5.3		6.0		7.0		9.2	ns
t_{OCLRY}	Output Asynchronous Clear to Y		4.7		5.3		6.0		7.0		9.2	ns
Predicted Input Routing Delays[2]												
t_{RD1}	FO = 1 Routing Delay		0.9		1.0		1.1		1.3		1.7	ns
t_{RD2}	FO = 2 Routing Delay		1.2		1.4		1.6		1.8		2.4	ns
t_{RD3}	FO = 3 Routing Delay		1.4		1.6		1.8		2.1		2.8	ns
t_{RD4}	FO = 4 Routing Delay		1.7		1.9		2.2		2.5		3.3	ns
t_{RD8}	FO = 8 Routing Delay		2.8		3.2		3.6		4.2		5.5	ns
I/O Module Sequential Timing (wrt IOCLK pad)												
t_{INH}	Input F-F Data Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{INSU}	Input F-F Data Setup	1.8		2.0		2.3		2.7		3.0		ns
t_{IDEH}	Input Data Enable Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{IDESU}	Input Data Enable Setup	5.8		6.5		7.5		8.6		8.6		ns
t_{OUTH}	Output F-F Data hold	0.7		0.8		0.9		1.0		1.0		ns
t_{OUTSU}	Output F-F Data Setup	0.7		0.8		0.9		1.0		1.0		ns
t_{ODEH}	Output Data Enable Hold	0.3		0.4		0.4		0.5		0.5		ns
f_{ODESU}	Output Data Enable Setup	1.3		1.5		1.7		2.0		2.0		ns

*Notes: **

1. *The –2 and –3 speed grades have been discontinued. Refer to PDN 0104, PDN 0203, PDN 0604, and PDN 1004 at http://www.microsemi.com/soc/support/notifications/default.aspx#pdn.*
2. *Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual worst-case performance. Post-route timing is based on actual routing delay measurements performed on the device prior to shipment.*

A1440A, A14V40A Timing Characteristics (continued)

***Table 2-27* • A1440A, A14V40A Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C**

I/O Module Input Propagation Delays		**–3 Speed[1]**		**–2 Speed[1]**		**–1 Speed**		**Std. Speed**		**3.3 V Speed[1]**		**Units**
Parameter/Description		**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	
t_{INY}	Input Data Pad to Y		2.8		3.2		3.6		4.2		5.5	ns
t_{ICKY}	Input Reg IOCLK Pad to Y		4.7		5.3		6.0		7.0		9.2	ns
t_{OCKY}	Output Reg IOCLK Pad to Y		4.7		5.3		6.0		7.0		9.2	ns
t_{ICLRY}	Input Asynchronous Clear to Y		4.7		5.3		6.0		7.0		9.2	ns
t_{OCLRY}	Output Asynchronous Clear to Y		4.7		5.3		6.0		7.0		9.2	ns
Predicted Input Routing Delays[2]												
t_{RD1}	FO = 1 Routing Delay		0.9		1.0		1.1		1.3		1.7	ns
t_{RD2}	FO = 2 Routing Delay		1.2		1.4		1.6		1.8		2.4	ns
t_{RD3}	FO = 3 Routing Delay		1.4		1.6		1.8		2.1		2.8	ns
t_{RD4}	FO = 4 Routing Delay		1.7		1.9		2.2		2.5		3.3	ns
t_{RD8}	FO = 8 Routing Delay		2.8		3.2		3.6		4.2		5.5	ns
I/O Module Sequential Timing (wrt IOCLK pad)												
t_{INH}	Input F-F Data Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{INSU}	Input F-F Data Setup	1.8		1.7		2.0		2.3		2.3		ns
t_{IDEH}	Input Data Enable Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{IDESU}	Input Data Enable Setup	5.8		6.5		7.5		8.6		8.6		ns
t_{OUTH}	Output F-F Data hold	0.7		0.8		0.9		1.0		1.0		ns
t_{OUTSU}	Output F-F Data Setup	0.7		0.8		0.9		1.0		1.0		ns
t_{ODEH}	Output Data Enable Hold	0.3		0.4		0.4		0.5		0.5		ns
f_{ODESU}	Output Data Enable Setup	1.3		1.5		1.7		2.0		2.0		ns

Notes:

1. *The –2 and –3 speed grades have been discontinued. Refer to PDN 0104, PDN 0203, PDN 0604, and PDN 1004 at http://www.microsemi.com/soc/support/notifications/default.aspx#pdn.*
2. *Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual worst-case performance. Post-route timing is based on actual routing delay measurements performed on the device prior to shipment.*

A1440A, A14V40A Timing Characteristics (continued)

***Table 2-28* • A1440A, A14V40A Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C**

I/O Module – TTL Output Timing[1]		**–3 Speed[2]**		**–2 Speed[2]**		**–1 Speed**		**Std. Speed**		**3.3 V Speed[1]**		**Units**
Parameter/Description		**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	
t_{DHS}	Data to Pad, High Slew		5.0		5.6		6.4		7.5		9.8	ns
t_{DLS}	Data to Pad, Low Slew		8.0		9.0		10.2		12.0		15.6	ns
t_{ENZHS}	Enable to Pad, Z to H/L, High Slew		4.0		4.5		5.1		6.0		7.8	ns
t_{ENZLS}	Enable to Pad, Z to H/L, Low Slew		7.4		8.3		9.4		11.0		14.3	ns
t_{ENHSZ}	Enable to Pad, H/L to Z, High Slew		7.4		8.3		9.4		11.0		14.3	ns
t_{ENLSZ}	Enable to Pad, H/L to Z, Low Slew		7.4		8.3		9.4		11.0		14.3	ns
t_{CKHS}	IOCLK Pad to Pad H/L, High Slew		8.5		8.5		9.5		11.0		14.3	ns
t_{CKLS}	IOCLK Pad to Pad H/L, Low Slew		11.3		11.3		13.5		15.0		19.5	ns
d_{TLHHS}	Delta Low to High, High Slew		0.02		0.02		0.03		0.03		0.04	ns/pF
d_{TLHLS}	Delta Low to High, Low Slew		0.05		0.05		0.06		0.07		0.09	ns/pF
d_{THLHS}	Delta High to Low, High Slew		0.04		0.04		0.04		0.05		0.07	ns/pF
d_{THLLS}	Delta High to Low, Low Slew		0.05		0.05		0.06		0.07		0.09	ns/pF
I/O Module – CMOS Output Timing[1]												
t_{DHS}	Data to Pad, High Slew		6.2		7.0		7.9		9.3		12.1	ns
t_{DLS}	Data to Pad, Low Slew		11.7		13.1		14.9		17.5		22.8	ns
t_{ENZHS}	Enable to Pad, Z to H/L, High Slew		5.2		5.9		6.6		7.8		10.1	ns
t_{ENZLS}	Enable to Pad, Z to H/L, Low Slew		8.9		10.0		11.3		13.3		17.3	ns
t_{ENHSZ}	Enable to Pad, H/L to Z, High Slew		7.4		8.3		9.4		11.0		14.3	ns
t_{ENLSZ}	Enable to Pad, H/L to Z, Low Slew		7.4		8.3		9.4		11.0		14.3	ns
t_{CKHS}	IOCLK Pad to Pad H/L, High Slew		9.0		9.0		10.1		11.8		14.3	ns
t_{CKLS}	IOCLK Pad to Pad H/L, Low Slew		13.0		13.0		15.6		17.3		22.5	ns
d_{TLHHS}	Delta Low to High, High Slew		0.04		0.04		0.05		0.06		0.08	ns/pF
d_{TLHLS}	Delta Low to High, Low Slew		0.07		0.08		0.09		0.11		0.14	ns/pF
d_{THLHS}	Delta High to Low, High Slew		0.03		0.03		0.03		0.04		0.05	ns/pF
d_{THLLS}	Delta High to Low, Low Slew		0.04		0.04		0.04		0.05		0.07	ns/pF

Notes:

1. *Delays based on 35 pF loading.*
2. *The –2 and –3 speed grades have been discontinued. Refer to PDN 0104, PDN 0203, PDN 0604, and PDN 1004 at http://www.microsemi.com/soc/support/notifications/default.aspx#pdn.*

A1460A, A14V60A Timing Characteristics (continued)

***Table 2-31* • A1460A, A14V60A Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C**

I/O Module Input Propagation Delays		**–3 Speed[1]**		**–2 Speed[1]**		**–1 Speed**		**Std. Speed**		**3.3 V Speed[1]**		**Units**
Parameter/Description		**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	
t_{INY}	Input Data Pad to Y		2.8		3.2		3.6		4.2		5.5	ns
t_{ICKY}	Input Reg IOCLK Pad to Y		4.7		5.3		6.0		7.0		9.2	ns
t_{OCKY}	Output Reg IOCLK Pad to Y		4.7		5.3		6.0		7.0		9.2	ns
t_{ICLRY}	Input Asynchronous Clear to Y		4.7		5.3		6.0		7.0		9.2	ns
t_{OCLRY}	Output Asynchronous Clear to Y		4.7		5.3		6.0		7.0		9.2	ns
Predicted Input Routing Delays[2]												
t_{RD1}	FO = 1 Routing Delay		0.9		1.0		1.1		1.3		1.7	ns
t_{RD2}	FO = 2 Routing Delay		1.2		1.4		1.6		1.8		2.4	ns
t_{RD3}	FO = 3 Routing Delay		1.4		1.6		1.8		2.1		2.8	ns
t_{RD4}	FO = 4 Routing Delay		1.7		1.9		2.2		2.5		3.3	ns
t_{RD8}	FO = 8 Routing Delay		2.8		3.2		3.6		4.2		5.5	ns
I/O Module Sequential Timing (wrt IOCLK pad)												
t_{INH}	Input F-F Data Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{INSU}	Input F-F Data Setup	1.3		1.5		1.8		2.0		2.0		ns
t_{IDEH}	Input Data Enable Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{IDESU}	Input Data Enable Setup	5.8		6.5		7.5		8.6		8.6		ns
t_{OUTH}	Output F-F Data hold	0.7		0.8		0.9		1.0		1.0		ns
t_{OUTSU}	Output F-F Data Setup	0.7		0.8		0.9		1.0		1.0		ns
t_{ODEH}	Output Data Enable Hold	0.3		0.4		0.4		0.5		0.5		ns
f_{ODESU}	Output Data Enable Setup	1.3		1.5		1.7		2.0		2.0		ns

Notes:

5. *The –2 and –3 speed grades have been discontinued. Refer to PDN 0104, PDN 0203, PDN 0604, and PDN 1004 at http://www.microsemi.com/soc/support/notifications/default.aspx#pdn.*
6. *Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual worst-case performance. Post-route timing is based on actual routing delay measurements performed on the device prior to shipment.*

Pin Descriptions

CLKA Clock A (Input)

Clock input for clock distribution networks. The Clock input is buffered prior to clocking the logic modules. This pin can also be used as an I/O.

CLKB Clock B (Input)

Clock input for clock distribution networks. The Clock input is buffered prior to clocking the logic modules. This pin can also be used as an I/O.

GND Ground

LOW supply voltage.

HCLK Dedicated (Hard-wired) Array Clock (Input)

Clock input for sequential modules. This input is directly wired to each S-Module and offers clock speeds independent of the number of S-Modules being driven. This pin can also be used as an I/O.

I/O Input/Output (Input, Output)

The I/O pin functions as an input, output, three-state, or bidirectional buffer. Input and output levels are compatible with standard TTL and CMOS specifications. Unused I/O pins are tristated by the Designer Series software.

IOCLK Dedicated (Hard-wired) I/O Clock (Input)

Clock input for I/O modules. This input is directly wired to each I/O module and offers clock speeds independent of the number of I/O modules being driven. This pin can also be used as an I/O.

IOPCL Dedicated (Hard-wired) I/O Preset/Clear (Input)

Input for I/O preset or clear. This global input is directly wired to the preset and clear inputs of all I/O registers. This pin functions as an I/O when no I/O preset or clear macros are used.

MODE Mode (Input)

The MODE pin controls the use of diagnostic pins (DCLK, PRA, PRB, SDI). When the MODE pin is HIGH, the special functions are active. When the MODE pin is LOW, the pins function as I/Os. To provide Actionprobe capability, the MODE pin should be terminated to GND through a 10K resistor so that the MODE pin can be pulled high when required.

NC No Connection

This pin is not connected to circuitry within the device.

PRA Probe A (Output)

The Probe A pin is used to output data from any user-defined design node within the device. This independent diagnostic pin can be used in conjunction with the Probe B pin to allow real-time diagnostic output of any signal path within the device. The Probe A pin can be used as a user-defined I/O when debugging has been completed. The pin’s probe capabilities can be permanently disabled to protect programmed design confidentiality. PRA is accessible when the MODE pin is HIGH. This pin functions as an I/O when the MODE pin is LOW.

PRB Probe B (Output)

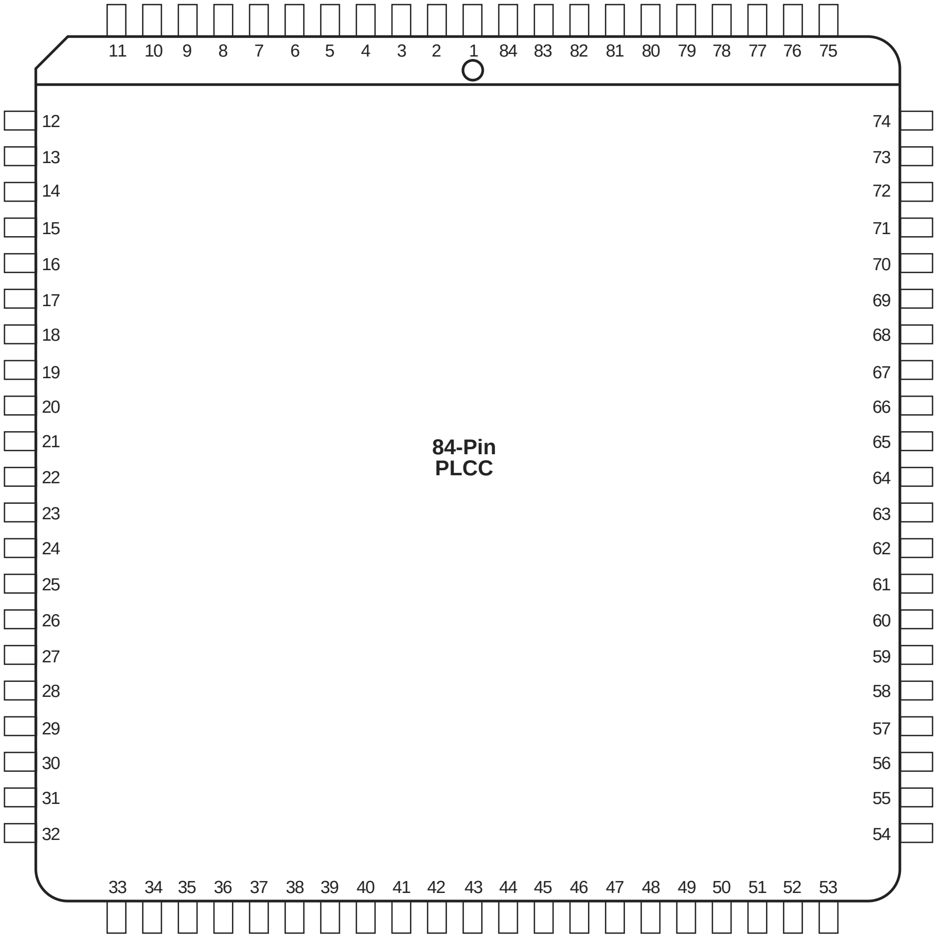
The Probe B pin is used to output data from any user-defined design node within the device. This independent diagnostic pin can be used in conjunction with the Probe A pin to allow real-time diagnostic output of any signal path within the device. The Probe B pin can be used as a user-defined I/O when debugging has been completed. The pin’s probe capabilities can be permanently disabled to protect programmed design confidentiality. PRB is accessible when the MODE pin is HIGH. This pin functions as an I/O when the MODE pin is LOW.

SDI Serial Data Input (Input)

Serial data input for diagnostic probe and device programming. SDI is active when the MODE pin is HIGH. This pin functions as an I/O when the MODE pin is LOW.

3 – Package Pin Assignments

PL84

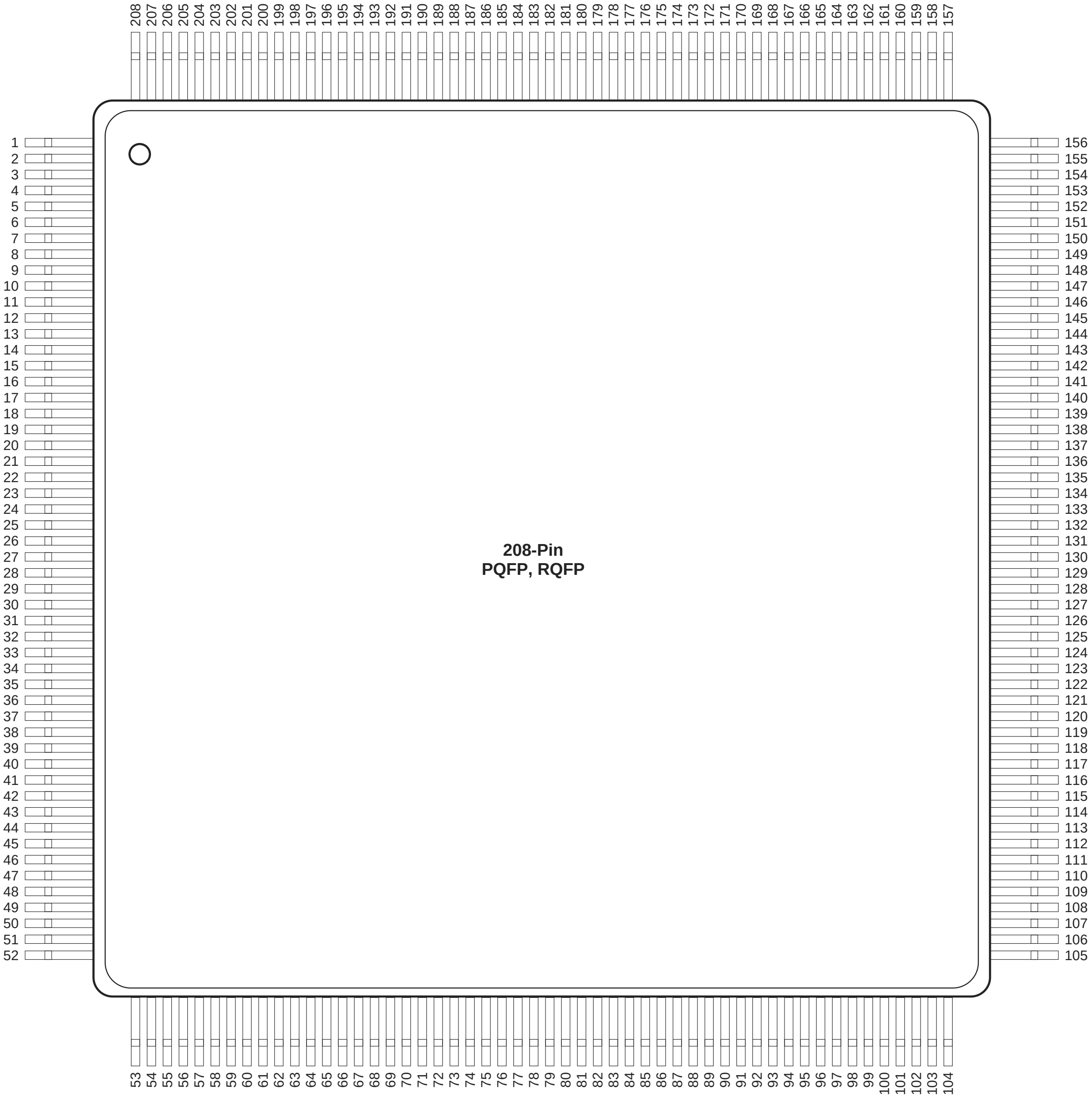


Note: This is the top view of the package.

Note

For Package Manufacturing and Environmental information, visit the Resource Center at http://www.microsemi.com/soc/products/solutions/package/docs.aspx.

PQ208, RQ208



Note: This is the top view of the package

Note

For Package Manufacturing and Environmental information, visit the Resource Center at http://www.microsemi.com/soc/products/solutions/package/docs.aspx

VQ100			
Pin Number	**A1415, A14V15 Function**	**A1425, A14V25 Function**	**A1440, A14V40 Function**
1	GND	GND	GND
2	SDI, I/O	SDI, I/O	SDI, I/O
7	MODE	MODE	MODE
8	VCC	VCC	VCC
9	GND	GND	GND
20	VCC	VCC	VCC
21	NC	I/O	I/O
34	PRB, I/O	PRB, I/O	PRB, I/O
35	VCC	VCC	VCC
36	GND	GND	GND
37	VCC	VCC	VCC
39	HCLK, I/O	HCLK, I/O	HCLK, I/O
49	SDO	SDO	SDO
50	IOPCL, I/O	IOPCL, I/O	IOPCL, I/O
51	GND	GND	GND
57	VCC	VCC	VCC
58	VCC	VCC	VCC
67	VCC	VCC	VCC
68	GND	GND	GND
69	GND	GND	GND
74	NC	I/O	I/O
75	IOCLK, I/O	IOCLK, I/O	IOCLK, I/O
87	CLKA, I/O	CLKA, I/O	CLKA, I/O
88	CLKB, I/O	CLKB, I/O	CLKB, I/O
89	VCC	VCC	VCC
90	VCC	VCC	VCC
91	GND	GND	GND
92	PRA, I/O	PRA, I/O	PRA, I/O
93	NC	I/O	I/O
100	DCLK, I/O	DCLK, I/O	DCLK, I/O

Notes:

1. All unlisted pin numbers are user I/Os.
2. NC denotes no connection.
3. MODE should be terminated to GND through a 10K resistor to enable Actionprobe usage; otherwise it can be terminated directly to GND.

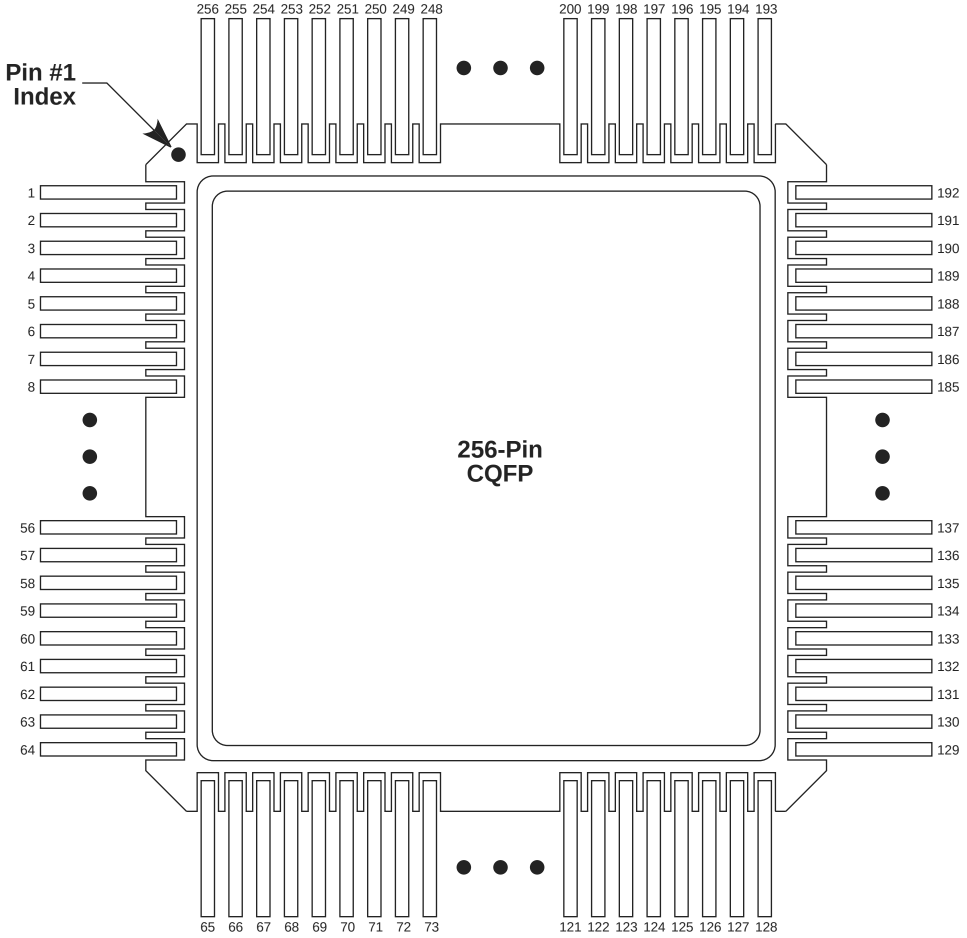
CQ132	
Pin Number	**A1425 Function**
1	NC
2	GND
3	SDI, I/O
9	MODE
10	GND
11	VCC
22	VCC
26	GND
27	VCC
34	NC
36	GND
42	GND
43	VCC
48	PRB, I/O
50	HCLK, I/O
58	GND
59	VCC
63	SDO
64	IOPCL, I/O
65	GND
66	NC

CQ132	
Pin Number	**A1425 Function**
67	NC
74	GND
75	VCC
78	VCC
89	VCC
90	GND
91	VCC
92	GND
98	IOCLK, I/O
99	NC
100	NC
101	GND
106	GND
107	VCC
116	CLKA, I/O
117	CLKB, I/O
118	PRA, I/O
122	GND
123	VCC
131	DCLK, I/O
132	NC

Notes:

1. All unlisted pin numbers are user I/Os.
2. NC denotes no connection.
3. MODE should be terminated to GND through a 10K resistor to enable Actionprobe usage; otherwise it can be terminated directly to GND.

CQ256



Note: This is the top view.

Note

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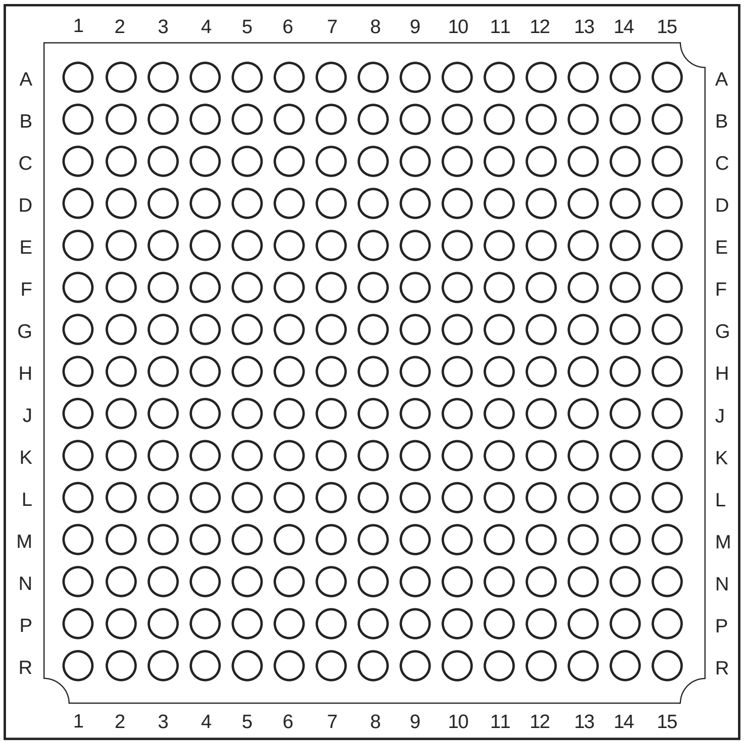
BG225



Note: This is the top view.

Note

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